

# Search Notes



Application/Control No.

10/766,374

Examiner

Wayne Langel

Applicant(s)/Patent under  
Reexamination

CHEN, SHAU-LIN F.

Art Unit

1754

## SEARCHED

Class	Subclass	Date	Examiner
423	239.1	9/23/2004	WAL
423	244.02	9/23/2004	WAL
<i>above to date 1-4-05 WAL</i>			

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
423	239.1	1-5-05	WAL
423	244.02	1-5-05	WAL

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR